Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/553,604	LONG ET AL.	
Examiner	Art Unit	
Phu K. Nguyen	2628	

SEARCHED			
Class	Subclass	Date	Examiner
345	619	9/10/2007	PN
	419	9/10/2007	PN
	421	9/10/2007	PN
	422	9/10/2007	PN
	629	9/10/2007	PN
	427, 428	9/10/2007	PN
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
WEST search - scan, depth, fill, texture, span, segment	9/10/2007	PN
Nonpatent IEEE, ACM, Google search es- scan, depth, fill, texture, span, segment	9/10/2007	PN
Inventor Name search	9/10/2007	PN
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